

# Υλοποίηση Ολοκληρωμένων Ψηφιακών Κυκλωμάτων

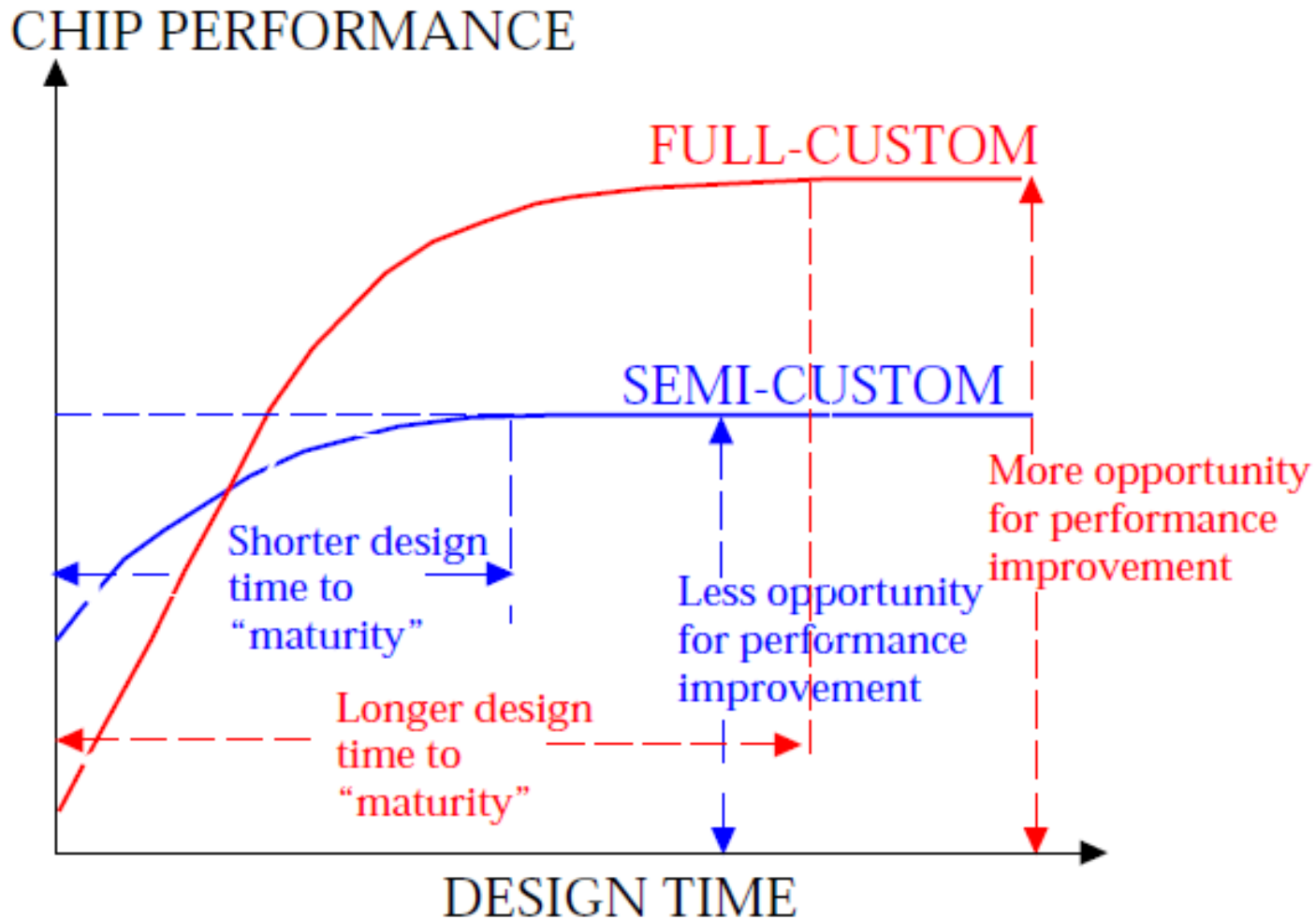
# ΒΙΒΛΙΟΓΡΑΦΙΑ

1. “Principles of CMOS LLSI Design”, N. Weste, K. Eshraghian, Addison Wesley.
2. “CMOS VLSI Design”, N. Weste, D. Harris, Addison Wesley.
3. “CMOS Digital Integrated Circuits”, S-M. Kang, Y. Leblebici, McGRAW-HILL.
4. “Digital Integrated Circuits”, J. Rabaey, A. Chandrakasan, B. Nokolic, PEARSON.

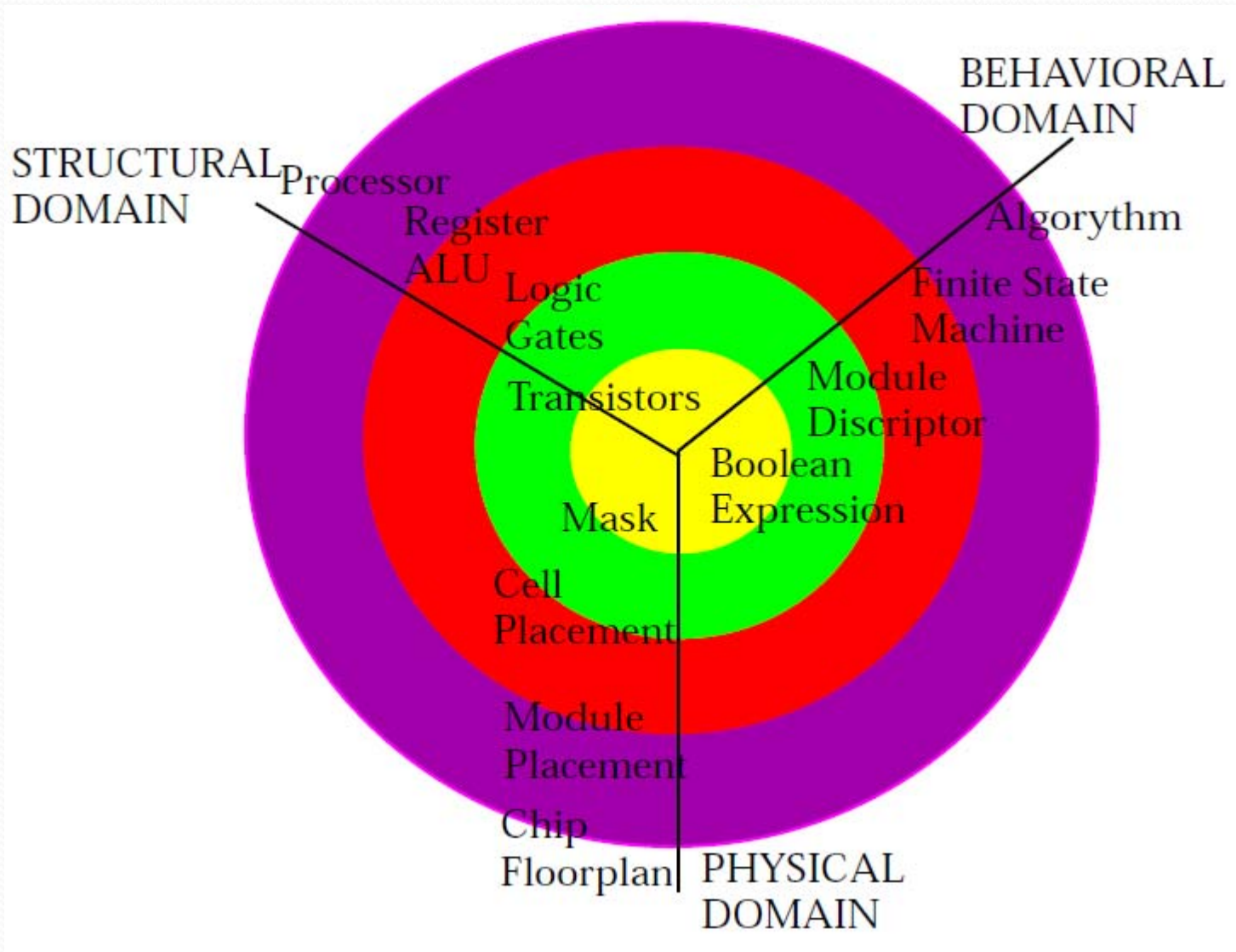
# ΣΤΟΧΟΙ ΤΗΣ ΜΟΝΟΛΙΘΙΚΗΣ ΟΛΟΚΛΗΡΩΣΗΣ

- > LESS AREA, MORE COMPACTNESS AT ALL SYSTEM LEVELS
- > LESS POWER CONSUMPTION
- > LESS TESTING (MORE COMPLEX TESTING)
- > HIGHER RELIABILITY, DUE TO IMPROVED ON-CHIP INTERCONNECTS
- > HIGHER SPEED DUE TO REDUCED INTERCONNECT LENGTH
- > SIGNIFICANT COST SAVINGS

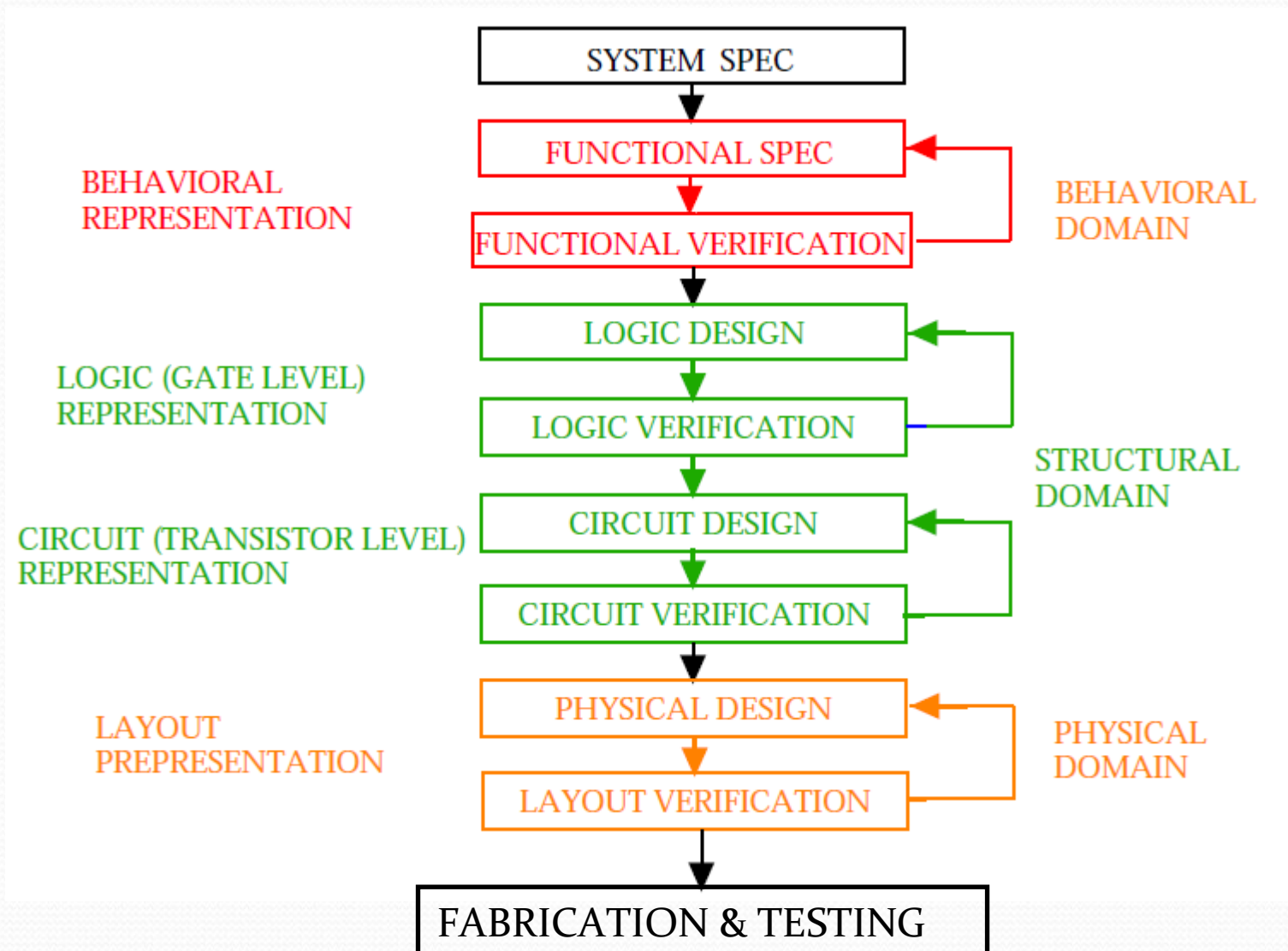
# ΕΠΙΔΡΑΣΗ ΤΗΣ ΜΕΘΟΔΟΛΟΓΙΑΣ ΣΧΕΔΙΑΣΗΣ



# ΣΧΕΔΙΑΣΤΙΚΑ ΕΠΙΠΕΔΑ ΑΦΑΙΡΕΣΗΣ



# ΡΟΗ ΣΧΕΔΙΑΣΗΣ VLSI ΚΥΚΛΩΜΑΤΩΝ

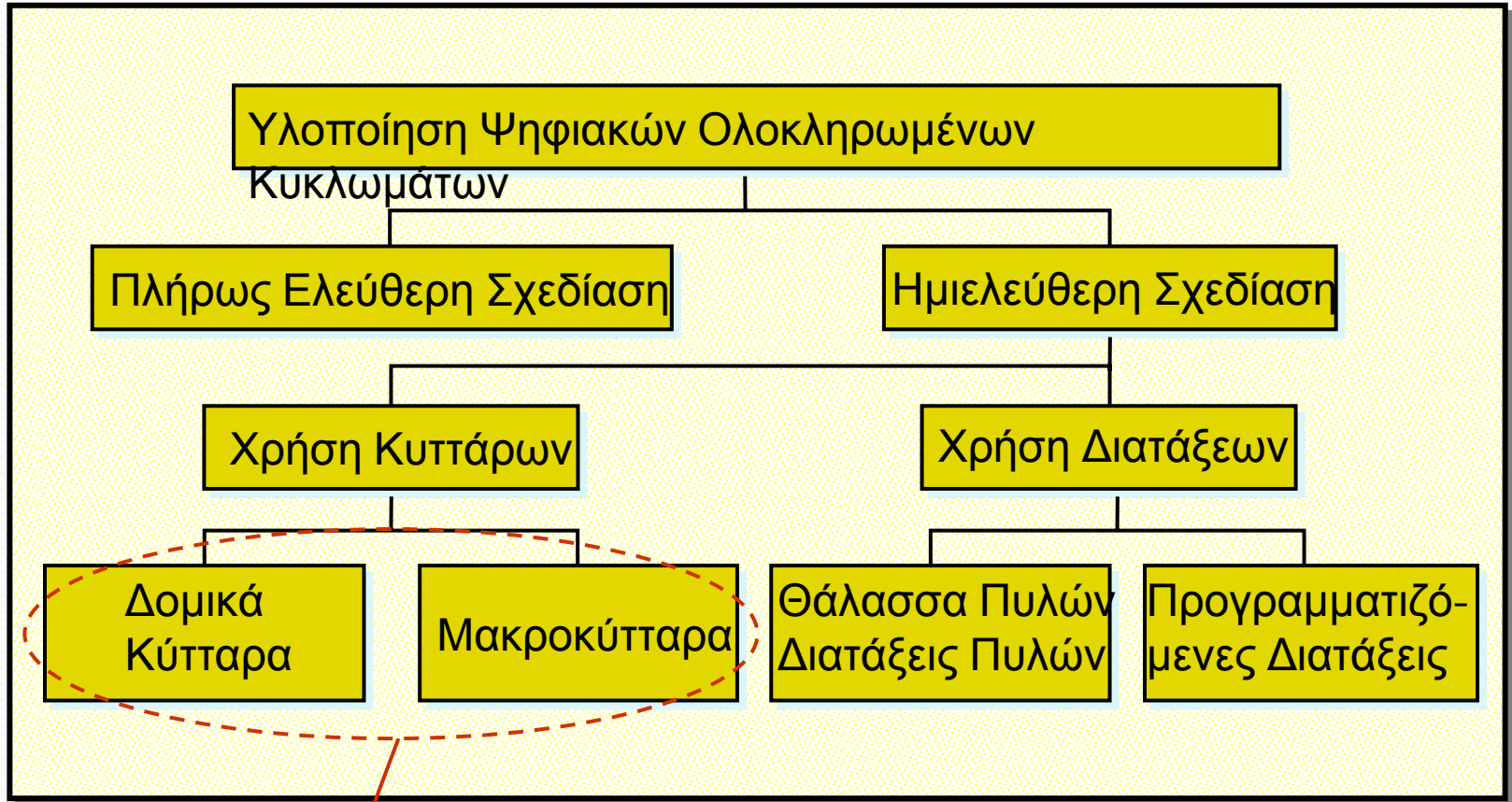


# ΣΤΡΑΤΗΓΙΚΕΣ ΔΟΜΗΜΕΝΗΣ ΣΧΕΔΙΑΣΗΣ

Techniques evolved for complex hardware and software projects.

- > **Hierarchy**: Subdivide the design into many levels of sub-modules
- > **Regularity**: Subdivide to max number of similar sub-modules at each level
- > **Modularity**: Define sub-modules unambiguously & well defined interfaces
- > **Locality**: Max local connections, keeping critical paths within module boundaries

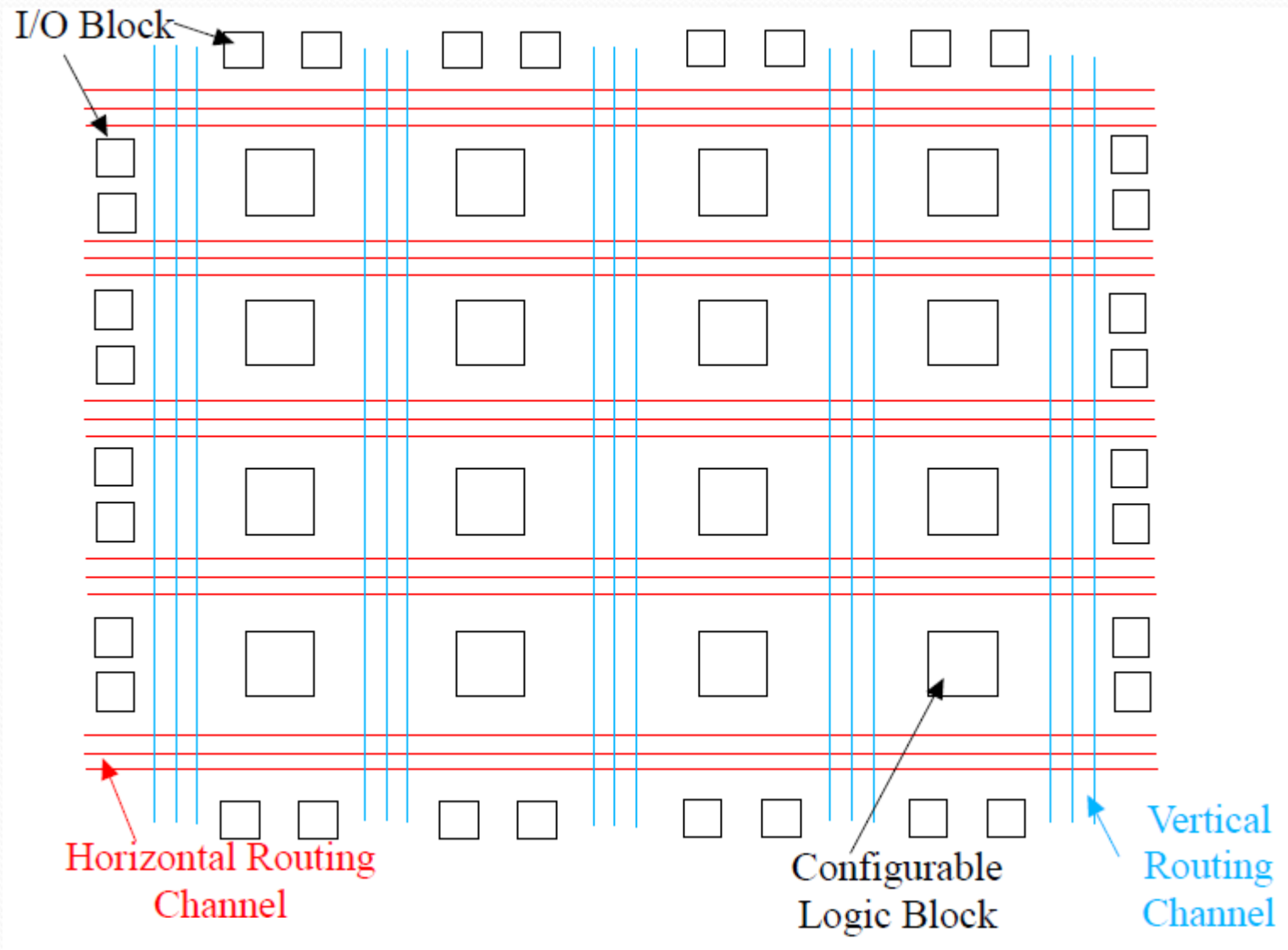
# ΣΧΕΔΙΑΣΤΙΚΕΣ ΕΠΙΛΟΓΕΣ



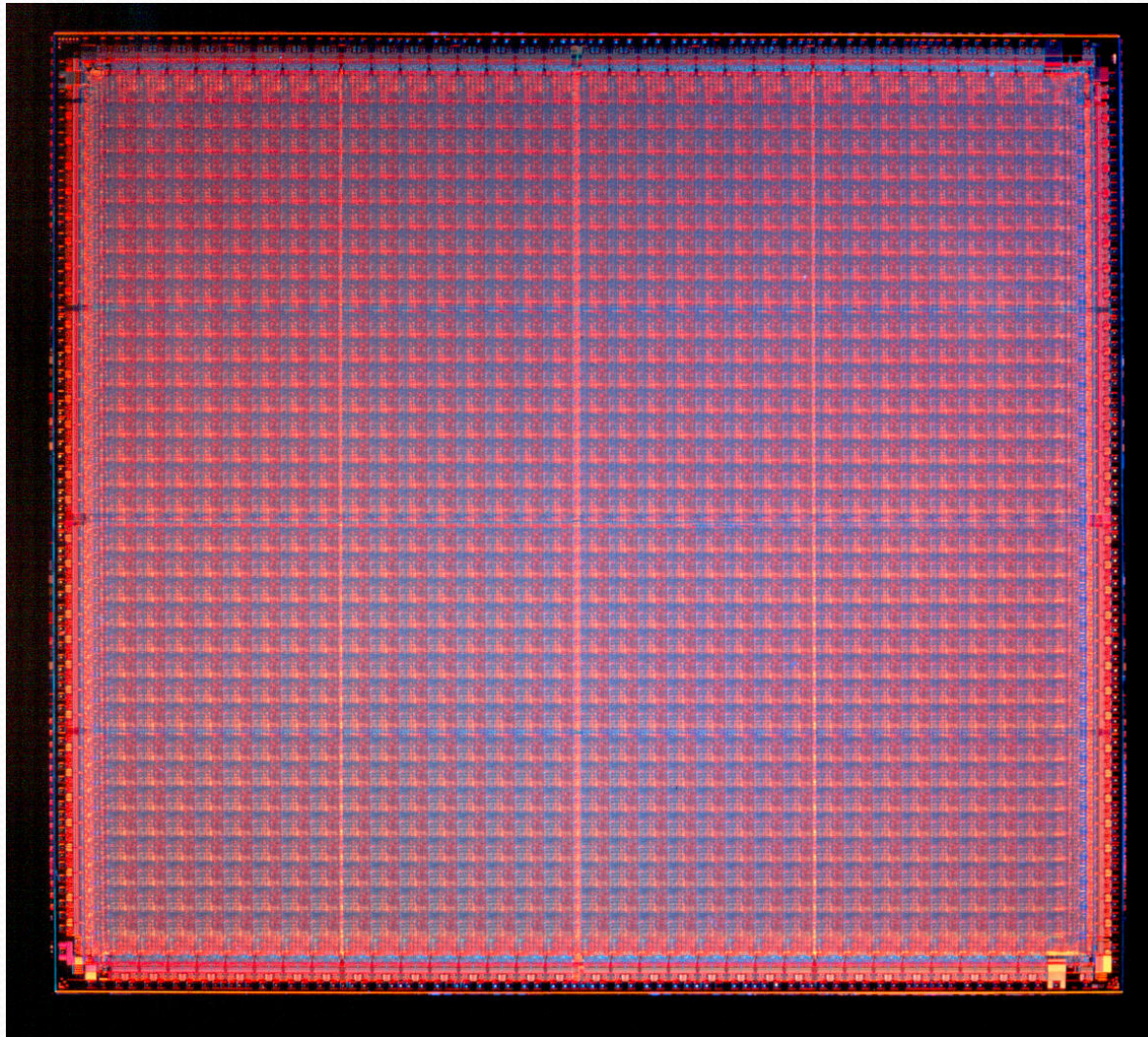
Σχεδίαση Ολοκληρωμένων Κυκλωμάτων Ειδικών Εφαρμογών  
Application Specific Integrated Circuits (ASICs)



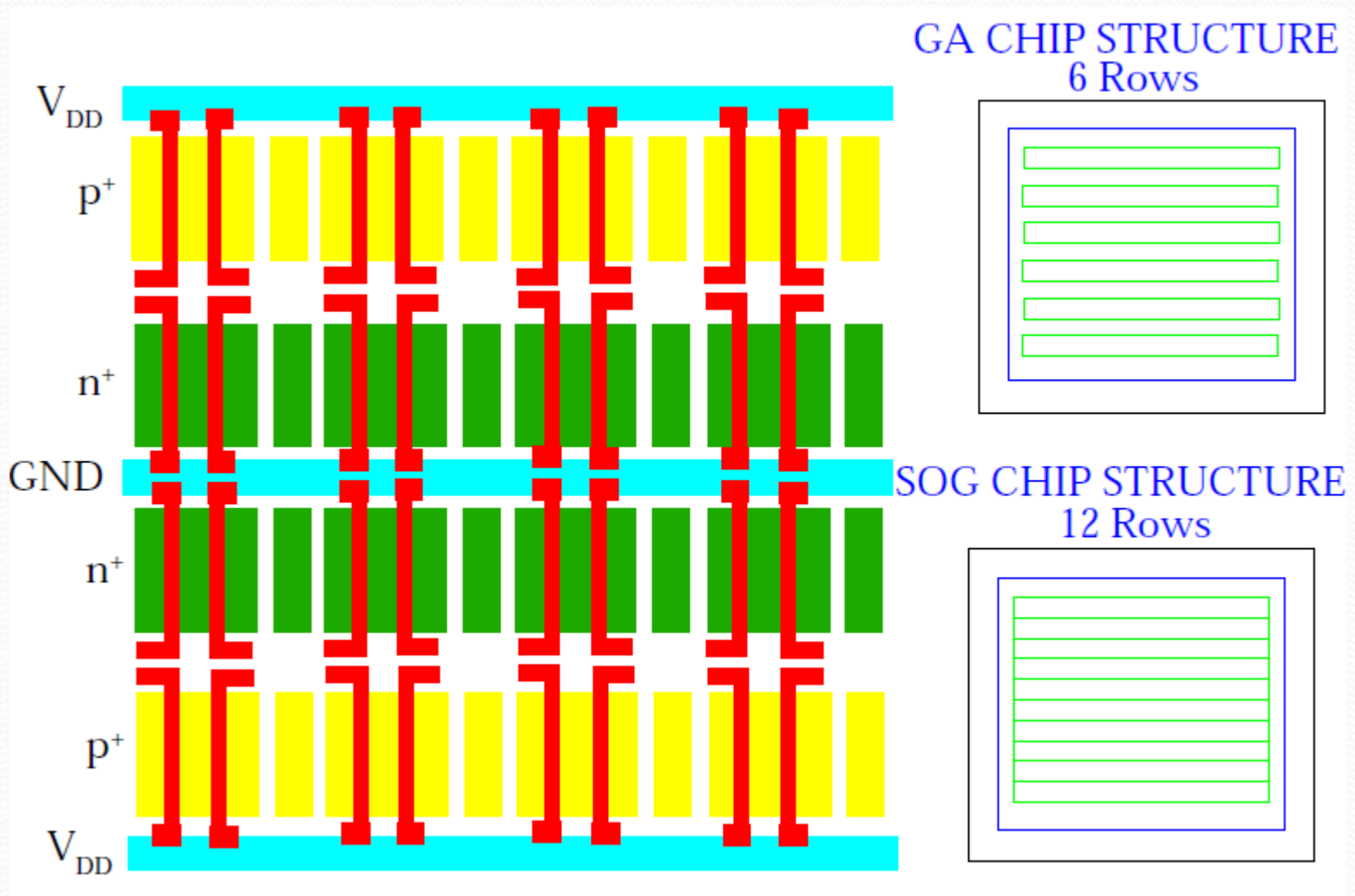
# FIELD PROGRAMMABLE GATE ARRAY (FPGA)



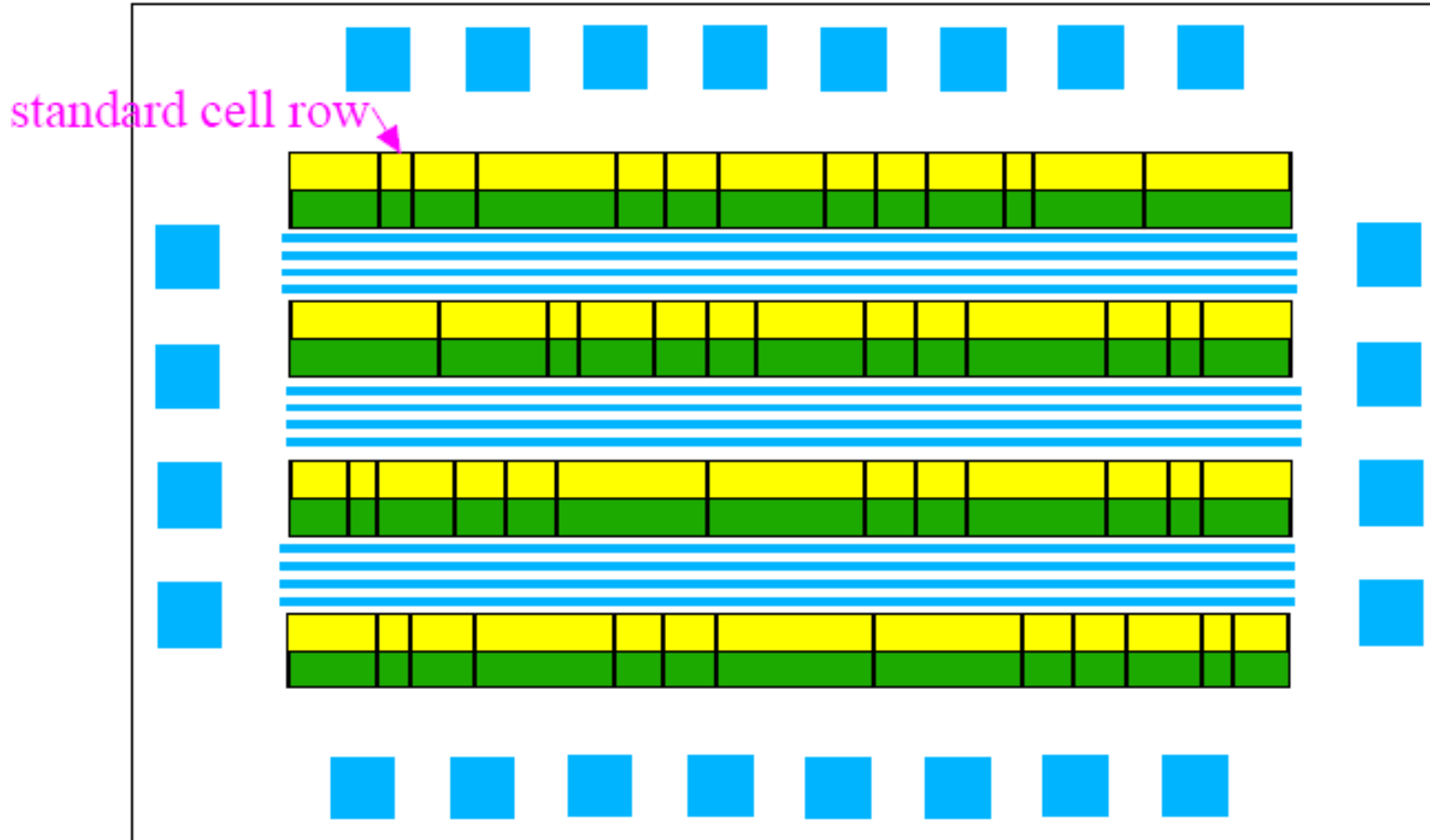
# ΟΛΟΚΛΗΡΩΜΕΝΟ FPGA



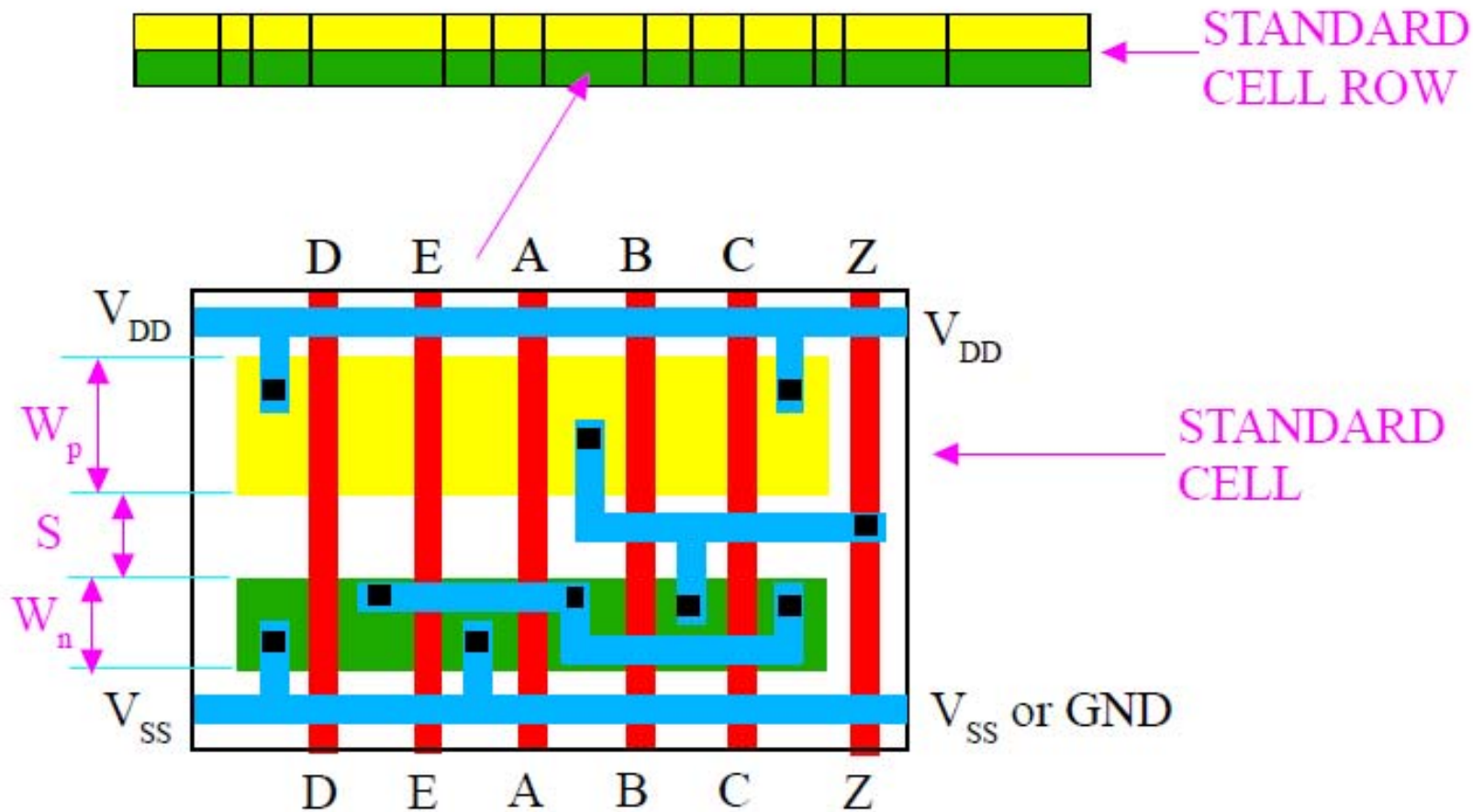
# SEA OF GATES / GATE ARRAY



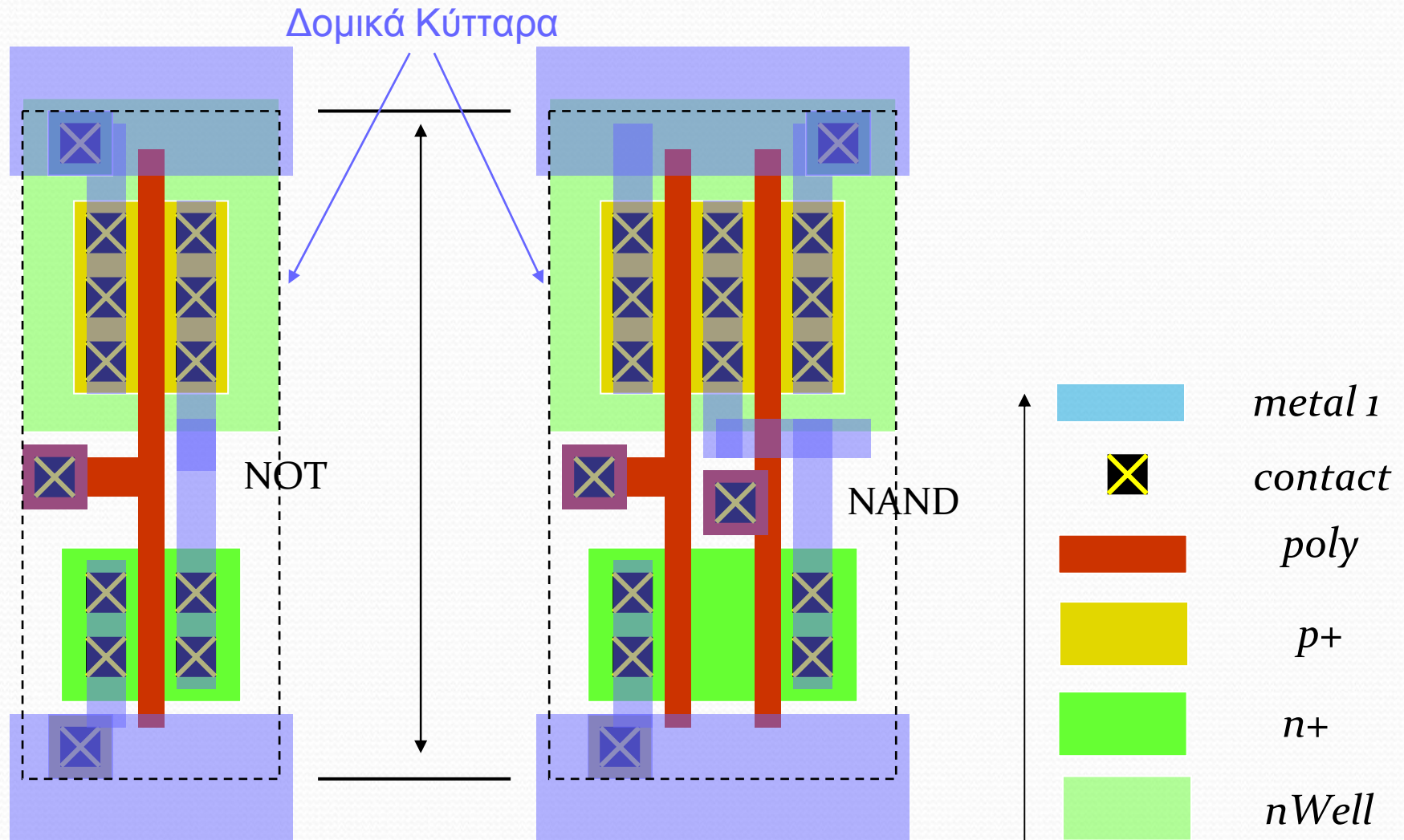
# ΣΧΕΔΙΑΣΗ ΜΕ ΔΟΜΙΚΑ ΚΥΤΤΑΡΑ (STANDARD CELLS)



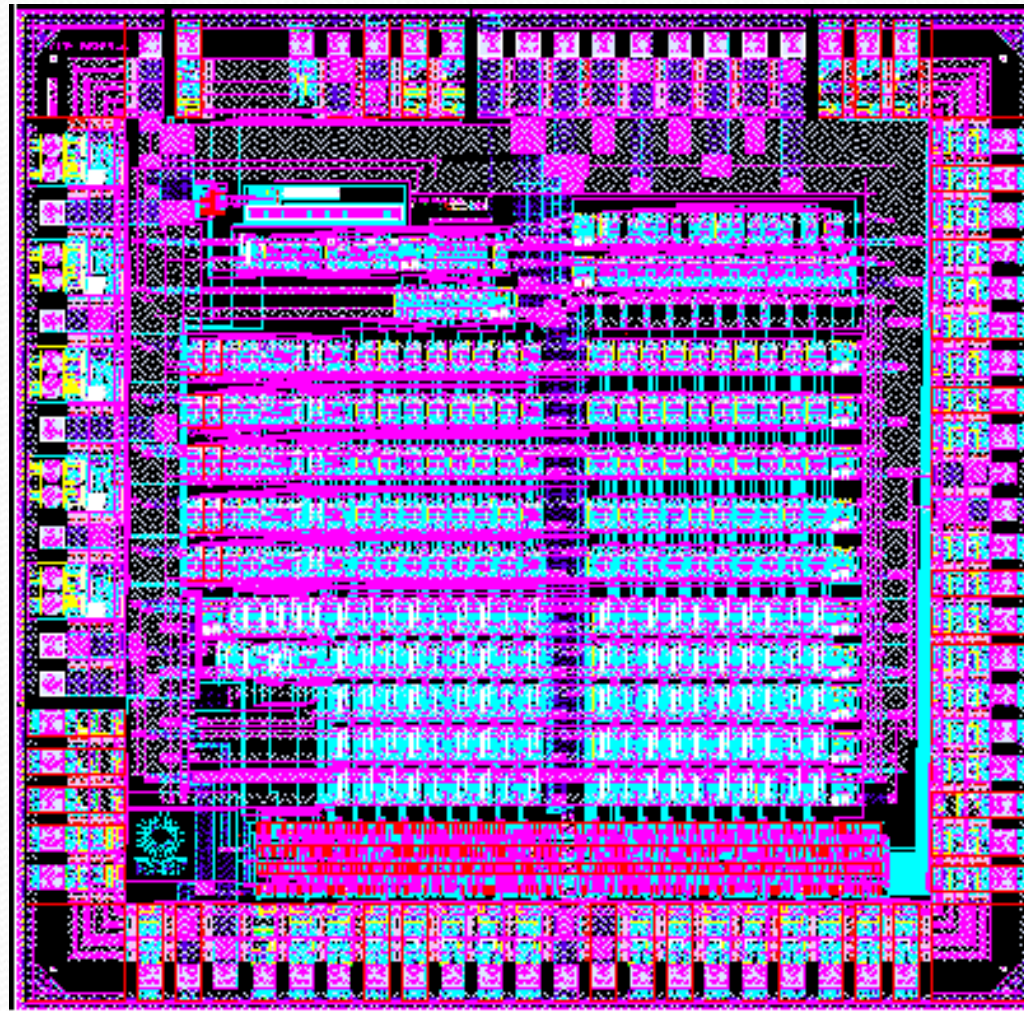
# ΔΟΜΙΚΑ ΚΥΤΤΑΡΑ (STANDARD CELLS)



# ΠΛΗΡΩΣ ΕΛΕΥΘΕΡΗ ΣΧΕΔΙΑΣΗ (FULL CUSTOM)



# ΠΛΗΡΗΣ ΕΙΚΟΝΑ ΟΛΟΚΛΗΡΩΜΕΝΟΥ



# ΠΟΙΟΤΗΤΑ ΣΧΕΔΙΑΣΗΣ

- > ACHIEVE SPECIFICATIONS (Static & Dynamic)
- > DIE SIZE
- > POWER DISSIPATION
- > TESTABILITY
- > YIELD AND MANUFACTURABILITY
- > RELIABILITY
- > TECHNOLOGY UPDATABLE



## -> TESTABILITY

- + generation of good test vectors
- + availability of reliable test fixture at speed
- + design of testable chip

## -> YIELD AND MANUFACTURABILITY

- + functional yield
- + parametric yield

## -> RELIABILITY

- + premature aging (Infant mortality)
- + ESD/EOS
- + latchup
- + on-chip noise and crosstalk
- + power and ground bouncing

## -> TECHNOLOGY UPDATABLE

- + Easily updated to new design rules

# ΠΑΚΕΤΑΡΙΣΜΑ (PACKAGING)

## DUAL IN-LINE PACKAGE (DIP)

1. ceramic or plastic pin-through-hole (PTH)
2. low cost, but large size
3. high lead inductance (22 - 36 nH)
4. max pin count usually 64

## PIN GRID ARRAY (PGA) PACKAGE

1. ceramic or plastic pin-through-hole (PTH)
2. higher pin count (100 - 400 pins)
3. higher cost than DIP

## CHIP CARRIER PACKAGE (CCP)

1. surface-mounted technology (SMT)
2. leadless chip carrier supports high pin count
3. more efficient use of PCB area than DIP or PGA

## MULTI-CHIP MODULE (MCM)

1. multiple chips assembled on a common substrate
2. high performance applications
3. most efficient use of PCB area

# ΕΡΓΑΛΕΙΑ ΣΧΕΔΙΑΣΗΣ (VLSI CAD TOOLS)

## CATEGORIES OF CAD TOOLS

1. High Level Synthesis (HDLs)
2. Logic Synthesis
3. Circuit Optimization
  - a. transistor sizing for min delays
  - b. process variations
  - c. statistical design
4. Layout
  - a. floorplanning
  - b. place & route
  - c. module generation
  - d. automatic cell placement and routing
5. Layout Extraction
6. Simulation (SPICE for circuit-level simulation)
7. Layout - Schematic Verification
8. Design Rule Check